

Search Notes

Application/Control No.

10/774,788

Examiner

Patrick J. Lee

Applicant(s)/Patent under
Reexamination

SHIN ET AL.

Art Unit

2878

SEARCHED

Class	Subclass	Date	Examiner
250	227.14, 227.16, 227.18, 227.23	11/17/2005	PL
385	12-13	11/17/2005	PL
385	31-32	11/17/2005	PL
385	37	11/17/2005	PL
356	32, 35.5	11/17/2005	PL
356	73.1	11/17/2005	PL

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
250	227.18	11/17/2005	PL

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Consulted w/ S. Allen	5/17/2005	PL
East (See attached)	5/18/2005	PL
East (See attached)	5/19/2005	PL
East (See attached)	9/19/2005	PL
East (see attached) - USPAT, US- PGPUB, EPO, JPO, DERWENT	11/17/2005	PL